

## Short Rietveld Course 2001 Introduction to *FullProf*

- ☞ Increasing the knowledge about powder diffraction.
- Web sites
- ☞ The program *FullProf*
- ☞ Examples: self-tutorials

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## Freely available software tools for crystallography

Lachlan M.D., Cranwick (L.Cranwick@ll.ac.uk)  
CCP14 Project for Single Crystal and Powder Diffraction  
<http://www.ccp14.ac.uk> ccp14@ccp14.ac.uk

### Downloading of Software

The above software and resources can be downloaded via the CCP14 site:

<http://www.ccp14.ac.uk>

Graphical tutorial run-through of most of this software is located via ("look before you try"):

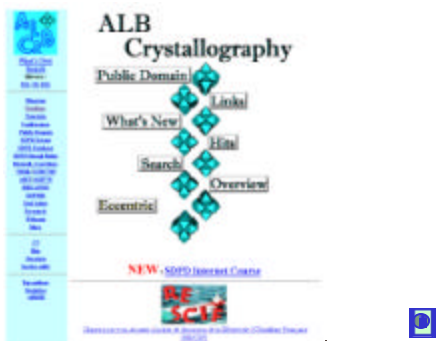
<http://www.ccp14.ac.uk/tutorial/>

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Armel Le Bail page: <http://sdpd.univ-lemans.fr>



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## What's *FullProf* ?

- ☞ A program for :
  - Simulation of powder diffraction patterns
  - Pattern decomposition  $\Rightarrow$  integrated intensities
  - Structure refinement
  - Powder and single crystal data
- ☞ Crystal and magnetic structures
- ☞ Multiple data sets: simultaneous treatment of several powder diffraction patterns (CW X-rays & neutrons, Energy dispersive X-rays, TOF neutron diffraction)
- ☞ Combined treatment of single crystal and powder data
- ☞ Structure determination capabilities: simulated annealing on integrated intensity data

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## A few words of history ...(1)

- Origins: DBW program, 1981 in Barcelona (thanks to Ray Young)
- Reorganization towards a structured programming within the FORTRAN 77 language, corrections of bugs, different ways of calculating R-factors, etc. Barcelona/Grenoble (1982-1987)
- Introduction of magnetic scattering, anisotropic broadening, profile matching (now known as Le Bail method), rigid bodies 1988-1992, Institute Laue-Langevin, Grenoble.

The name *FullProf* is adopted in 1990

"FULLPROF: A Program for Rietveld Refinement and Pattern Matching Analysis"  
J. Rodriguez-Carvajal  
Powder Diffraction, Satellite meeting of the XV congress of the International Union of Crystallography, Toulouse 16-19 July (1990)

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## A few words of history ...(2)

- Improvements of magnetic scattering options, new peak shapes, single crystal and integrated intensities options, ...  
Distribution by anonymous ftp in 1993. LLB, Orsay (near Paris)
- Introduction of a rudimentary option for handling Time of Flight neutron powder diffraction data in 1996.
- WinPLOT and Windows version of FullProf, distribution via the LLB Web site. Progressive conversion to Fortran 90 style and conventions (1998).
- Complete reorganization of the code within the new Fortran 90 language. Programmed in the subset ELF90. Multiple data sets, TOF improvements (Barcelona, Argonne, Orsay, 1999 ...)

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### **FullProf Web site:**

<http://www-llb.cea.fr/fullweb/powder.htm>  
or  
<ftp://charybde.saclay.cea.fr/pub/divers>

Version 3.5 (FORTRAN 77, most common platforms)  
<ftp://charybde.saclay.cea.fr/pub/divers/fullp>  
(single pattern, discontinued version, only action: correction of bugs)

FullProf.9x & FullProf.2k (Fortran 90 subset ELF90)  
Windows 9x/2k, Windows NT, MacOS, Linux  
<ftp://charybde.saclay.cea.fr/pub/divers/fullprof.98>  
<ftp://charybde.saclay.cea.fr/pub/divers/fullprof.2k>

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## **New features of *FullProf***

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## **New features of *FullProf* (1)**

<http://www-llb.cea.fr/fullweb/powder.htm>

- Full multipattern capabilities: joint refinements of neutron and X-ray patterns, different wavelengths, detector banks, etc.
- Optimization for common or routine problems
- Automatic attribution of code parameters, distances, angles and bond-valence calculations
- Form factor refinements

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## **New features of *FullProf* (2)**

<http://www-llb.cea.fr/fullweb/powder.htm>

- Generalization of anisotropic broadening formulation for micro-strains and size effects.
- Interpretation of micro-structural parameters
- New formulation of T.O.F. versus d-spacing (Jason Hodges, Argonne) fully implemented

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## **New features of *FullProf* (3)**

<http://www-llb.cea.fr/fullweb/powder.htm>

- Superstructures treated within the basic subcell and Fourier coefficients of displacement vectors
- Simulated annealing for solving crystal and magnetic structures.
- New formulation for rigid bodies: Z-matrices (only partially implemented at present)

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## **Refinement of multiple data sets...**

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```

COMM MultiPattern: PbSO4 DIA(ILL) + RX
NPATT 2
W_PAT 0.500 0.500
! Nph Dum Ias Hre Cry Opt Aut
! 1 0 0 0 0 1
! Job Npr Nba Nex Nec Nor Iwg Ilo Res Ste Uni Cor Asym
! 1 7 0 2 0 0 0 0 0 0 0 0 0 0 0
! 0 5 0 2 0 0 0 0 0 0 0 0 0 0 0
! File names of data(patterns) files
pbso4
pbsox
!
! Mat Per Syo Rpa Sym Sho
! 0 2 0 0 0 0
! Ipr Ppl Ioc Ls1 Ls2 Ls3 Prf Ins Hkl Fou Ana
! 0 0 1 0 0 0 0 1 6 1 1 0
! 0 0 1 0 0 0 1 0 1 1 0
!
! lambda1 Lambda2 Ratio Bkpos Wdt Cthm muR AsyLim Rpolar ->Patt1
1.913615 1.913615 1.0000 70.0000 6.0000 0.0000 0.0000 160.00 0.0000
!
! lambda1 Lambda2 Ratio Bkpos Wdt Cthm muR AsyLim Rpolar ->Patt2
1.540500 1.544400 0.5000 50.0000 6.0000 0.8000 0.0000 160.00 0.0000
!
.....

```

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```

INCY Eps R_at R_an R_pr R_gl
3 0.10 1.00 1.00 1.00 1.00
! Thmin Step Thmax PSD Sento -> Patt#: 1
! 10.0000 0.0500 155.4500 0.000 0.000
! Thmin Step Thmax PSD Sento -> Patt#: 2
! 10.0000 0.0250 160.0000 0.000 0.000
! Excluded regions (LowT HighT) for Pattern# 1
! 0.00 10.00
! 154.00 180.00
! Excluded regions (LowT HighT) for Pattern# 2
! 0.00 10.00
! 154.00 180.00
!
50 !Number of refined parameters
!
! Zero Code Sycos Code Sysin Code Lambda Code MORE ->Patt# 1
! -0.0864 81.00 0.0000 0.00 0.0000 0.00 1.913615 161.00 0
! Background coefficients/codes for Pattern# 1
! 207.53 40.752 45.464 -26.893 -42.644 14.787
! 501.000 31.000 41.000 51.000 61.000 71.000
!
! Zero Code Sycos Code Sysin Code Lambda Code MORE ->Patt# 2
! 0.0062 91.00 0.0000 0.00 0.0000 0.00 0.000000 0.00 0
! Background coefficients/codes for Pattern# 2
! 128.46 35.422 -65.957 -23.530 88.944 -29.782
! 101.000 111.000 121.000 131.000 141.000 151.000
!
.....

```

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```

-----
! Data for PHASE number: 1 ==> Current R_Bragg for Pattern# 1: 4.23
! Data for PHASE number: 1 ==> Current R_Bragg for Pattern# 2: 4.79
-----
PbSO4
! Mat Dis Mom Jbt Isy Str Furth ATZ Nvk More
! 5 0 0 0 0 0 0 0.0000 0 1
! Jvi Jdi Hel Sol Mom Ter
! 0 3 0 0 0 0
! Contributions (O/I) of this phase to the 2 patterns
! 1
! Irf Npr Jtyp for Pattern# 1
! 0 7 1
! Pr1 Pr2 Pr3 Brind. RmuA RmuB RmuC for Pattern# 1
! 0.000 0.000 1.000 1.000 0.000 0.000 0.000
! Irf Npr Jtyp for Pattern# 2
! 0 5 0
! Pr1 Pr2 Pr3 Brind. RmuA RmuB RmuC for Pattern# 2
! 0.000 0.000 1.000 1.000 0.000 0.000 0.000
!
! Max_dst(dist) (angles) Bond-Valence Calc.
! 3.5000 0.0000 BVS
! N_cations N_anions Tolerance(%) / Name or cations/ and Anions
! 2 1 0.00
PB+2 S+6
Q-2
P n m a <--Space group symbol
.....

```

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```

! Atom Typ X Y Z Biso Occ In Fin N_t Poi /Codes
Pb PB 0.18771 0.25000 0.16728 1.37185 0.50000 0 0 0 1
! 171.00 0.00 181.00 281.00 0.00
S S 0.06516 0.25000 0.68359 0.49027 0.50000 0 0 0 2
! 191.00 0.00 201.00 291.00 0.00
O1 O 0.90771 0.25000 0.59525 1.94953 0.50000 0 0 0 3
! 211.00 0.00 221.00 301.00 0.00
O2 O 0.19359 0.25000 0.54312 1.44874 0.50000 0 0 0 3
! 231.00 0.00 241.00 311.00 0.00
O3 O 0.08059 0.02719 0.80898 1.29124 1.00000 0 0 0 3
! 251.00 261.00 271.00 321.00 0.00
!----- Profile Parameters for Pattern # 1
! Scale Shapel Bov Str1 Str2 Str3 Strain-Model
! 1.4742 0.0000 0.0000 0.0000 0.0000 0.0000 0
! 11.00000 0.00 0.00 0.00 0.00 0.00
! V W X Y
! 0.15742 -0.46171 0.41993 0.00000 0.09353 0.00000 0.00000 0
! 381.00 391.00 401.00 0.00 411.00 0.00 0.00
! a b c alpha beta gamma
! 8.485911 5.401731 6.964305 90.000000 90.000000 90.000000
! 351.00000 361.00000 371.00000 0.00000 0.00000 0.00000
! Pref1 Pref2 Asy1 Asy2 Asy3 Asy4
! 0.00000 0.00000 0.36082 0.03665-0.30050 0.00000
! 0.00 0.00 421.00 431.00 441.00 0.00
!----- Profile Parameters for Pattern # 2
! Scale Shapel Bov Str1 Str2 Str3 Strain-Model
! 0.47250E-03 0.0000 0.0000 0.0000 0.0000 0.0000 0
! 21.00000 0.00 0.00 0.00 0.00 0.00
.....

```

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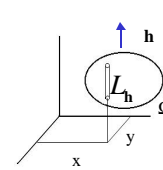
**Microstructural effects**

**Anisotropic peak broadening**

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**Anisotropic broadening due to size effects**

Scherrer formula:  $b_h = \frac{l}{D_h \cos \theta}$

$$D_h = \frac{1}{V} \iiint_{\Omega} L_h(x, y) d^3 \mathbf{r}$$


$D_h$  : volume average of column lengths along  $h=(hkl)$  for all crystallites in the sample

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### Microstructural effects are simulated in the Rietveld Method using the Voigt approximation (Langford & Louër).

Special expressions for anisotropic broadening due to size effects:

- Infinite needles
- Infinite platelets
- Finite cylinders

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### Spherical harmonics to simulate the average form of crystallites

$$\frac{1}{D_h} = \sum_{lmp} a_{lmp} P_{lm}(\cos \Theta_h) \begin{Bmatrix} \cos m \Phi_h \\ \sin m \Phi_h \end{Bmatrix}; \quad p = +/ -$$

$(\Theta_h, \Phi_h)$  : Polar angles of reciprocal vector  $\mathbf{h}$  w.r.t. crystal frame

$$FWHM = \frac{kI}{\cos \Theta_h} \sum_{lmp} a_{lmp} P_{lm}(\cos \Theta_h) \begin{Bmatrix} \cos m \Phi_h \\ \sin m \Phi_h \end{Bmatrix}$$

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### Anisotropic strain broadening

**Phenomenological model:** strains considered as fluctuations and correlation between metric parameters  
J. Rodriguez-Carvajal *et al* (J. Phys. Cond. Matt. 3, 3215 (1991))

$$M_{hkl} = \frac{1}{d_{hkl}^2} = M(\mathbf{a}_i; hkl)$$

The metric parameters  $\mathbf{a}_i$  (direct, reciprocal or any combination) are considered as stochastic variables with a Gaussian distribution characterized by :

- the mean  $\langle \mathbf{a}_i \rangle$  and
- the variance-covariance matrix  $C_{ij}$

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**The mean and the variance of the function  $M_{hkl}$  are given by** (JRC *et al*, J. Phys. Cond. Matt. 3, 3215 (1991)) :

$$\langle M_{hkl} \rangle = M(\langle \mathbf{a}_i \rangle; hkl)$$

$$s^2(M_{hkl}) = \sum_{i,j} C_{ij} \frac{\partial M}{\partial \mathbf{a}_i} \frac{\partial M}{\partial \mathbf{a}_j}$$

$C_{ij}$  contains 21 parameters,  
15 independent

If the metric parameters are taken as the coefficients of the quadratic form:  $\frac{1}{d_{hkl}^2} = Ah^2 + Bk^2 + Cl^2 + Dkl + Ehl + Fhk$   
 $\{\mathbf{a}_i\} = \{A, B, C, D, E, F\}$

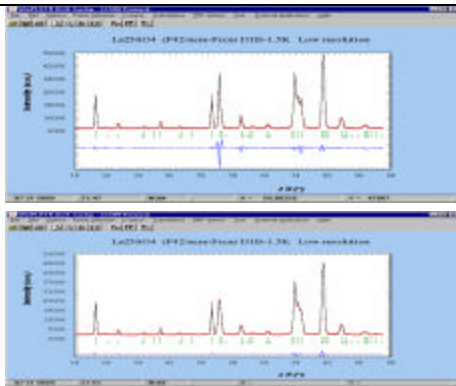
$$s^2(M_{hkl}) = \sum_{HKL} S_{HKL} h^H k^K l^L$$

$\{H+K+L=4\}$

P. W. Stephens,  
J. Appl. Cryst. 32, 281 (1999)

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### Simulated Annealing ....

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Classically, crystal structure determination is considered as a process to determine the “phases” of the structure factors

$$\mathbf{r}(\mathbf{r}) = \sum_{\mathbf{h}} F_{\mathbf{h}} \exp \{-2\mathbf{p} \cdot i\mathbf{h}\mathbf{r}\}$$

$$\mathbf{r}(\mathbf{r}) = \sum_{\mathbf{h}} |F_{\mathbf{h}}| \exp \{-2\mathbf{p} \cdot i(\mathbf{h}\mathbf{r} + \Phi_{\mathbf{h}})\}$$

For a centrosymmetric structure  $\Phi_{\mathbf{h}}$  is 0 or 1/2

The knowledge of all phases for the measured structure factors provides a density map from which the structure is derived (chemically recognised).

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The resolution of the “phase problem” is the goal of the crystal structure determination methods

Direct Methods tackle the problem looking for phase relations (tangent formula) between structure factors of different reflections

Direct methods need a high number of reflections and good resolution (powders)

Direct methods are generally very efficient

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But ...

sometimes direct methods fail in solving particular structures  
or  
cannot be applied because poor data quality (low resolution)

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### Structure factor calculation

$$F(\mathbf{h}) = \sum_{j=1}^n O_j f_j(\mathbf{h}) T_j \sum_s \exp \{2\mathbf{p} \cdot i[\mathbf{h}\{\mathbf{S}|\mathbf{t}\}_s \mathbf{r}_j]\}$$

If the chemical composition and the space group are known we have to determine just the **3n variables**

$$F_{obs}(\mathbf{h})_r \approx \left| \sum_{j=1}^n O_j f_j T_j \sum_s \exp \{2\mathbf{p} \cdot i[\mathbf{h}\{\mathbf{S}|\mathbf{t}\}_s \mathbf{r}_j]\} \right|_r$$

$$\mathbf{h}_r = (h, k, l)_r \quad (r = 1, 2, \dots, N)$$

$$\mathbf{r}_j = (x_j, y_j, z_j) \quad (j = 1, 2, \dots, n)$$

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### Direct space methods:

- Look directly for atom positions explaining the experimental data
- Minimize a reliability factor with respect to the “configuration vector” or “chromosome”

$$\left| \begin{array}{c} \text{ } \end{array} \right\rangle$$

$$R(\mathbf{v}) = c \sqrt{\sum_{\mathbf{h}}^N |F_{obs}(\mathbf{h}) - F_{calc}(\mathbf{h}, \mathbf{v})|^2}$$

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### Solving Crystal structures by Powder diffraction and direct space methods

(1) Indexing the powder diffraction pattern: *DICVOL*, *TREOR*, *ITO*, ... (WinPLOT)

(2) Extracting integrated intensities (*FullProf*) Space Group determination

(3) Use *ExPo* to solve the structure

(4) If *ExPo* fails then Use Simulated Annealing (*FullProf*) or Genetic Algorithms

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## Simulated Annealing (SA):

The SA method is a general purpose optimization technique for large combinatorial problems introduced by:

Kirpatrick, Gelatt and Vecchi, *Science* **220**, 671-680 (1983).

The function,  $E(\mathbf{w})$  to be optimized with respect to the configuration described by the vector state  $\mathbf{w}$  is called the “cost” function.

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## Simulated Annealing (SA):

The SA method applied to structural problems:

•J. Pannetier, J. Bassas-Alsina, J. Rodríguez-Carvajal and V. Caignaert, *Nature* **346**, 343-345 (1990)

•J.M. Newsam, M.W. Deem and C.M. Freeman, Accuracy in Powder Diffraction II. NIST Special Publ. No. **846**, 80-91 (1992)

•J. Rodríguez-Carvajal, *Physica B* **192**, 55-69 (1993)

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## The Simulated Annealing Algorithm

```
begin
  Initialise (set to zero useful quantities, do preliminary calculations )
   $\tau = 1$ 
  do
    Perturb the system :
     $\mathbf{w}_{old} \rightarrow \mathbf{w}_{new}, \Delta = E(\mathbf{w}_{new}) - E(\mathbf{w}_{old})$ 
    if  $\Delta \leq 0$  then accept, else
    if  $\exp(-\Delta/T_{\tau}) > \text{random}[0,1]$  then accept
    if accept then Update (replace  $\mathbf{w}_{old}$  by  $\mathbf{w}_{new}$ )
  until equilibrium is approached closely enough (Ncyc)
   $T_{\tau+1} = f(T_{\tau})$  (decrease temperature, usually  $T_{\tau+1} = q T_{\tau}$ ,  $q=0.9$ )
   $\tau = \tau + 1$ 
  until stop criterion is true (maximum  $\tau$ , convergence, low % accepted...)
end
```

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```
COMM Ab initio structure solution of PbSO4 (Simulated Annealing, data D1A-ILL)
! Files => DAT-file: pb_san, PCR-file: pb_san
! Job Npr Nph Nba Nbx Nbc Nbr Dum Iwg Ilo Ias Res Ste Nre Cry Uni Cor Opt Aut
! 1 0 1 0 0 0 0 0 0 0 0 0 0 0 0 12 3 0 0 0 0
! Ipr Ppl Loc Mat Per Ls1 Ls2 Ls3 Syo Prf Ins Spa Sym Hkl Fou Sho Ana
! 0 0 1 0 1 0 0 0 0 0 0 1 0 0 0 0 0 0 0 0 0
!
! INCY Eps R_at R_an R_pr R_gl Thmin Step Thmax PSD Sent0
! 1 0.10 1.00 1.00 1.00 1.00 15.0000 0.0200 120.0400 0.000 0.000
!
! 12 !Number of refined parameters
!-----
! Data for PHASE number: 1 ==> Current R_Bragg for Pattern# 1: 7.86
!-----
PbSO4
! Nat Dis Mom Pr1 Pr2 Pr3 Jbt Irf Isy Str Furth ATZ Nvk Npr More
! 5 0 0 0.0 0.0 1.0 0 4 0 0 0 0.00 0 7 0
!
! P n a a <--Space group symbol
! Atom Typ X Y Z Biso Occ In Fin N_t Poi /Codes
Pb PB 0.81174 0.23348 0.83479 1.42124 0.50000 0 0 0 0
S S 11.00 21.00 31.00 0.00 0.00
S S 0.93358 0.23348 0.32454 0.41603 0.50000 0 0 0 0
. . . . .
```

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```
! Sc1 Sc2 Sc3 Sc4 Sc5 Sc6
1.531 0.000 0.000 0.000 0.000 0.000
0.00 0.00 0.00 0.00 0.00 0.00
! a b c alpha beta gamma
8.485130 5.402066 6.964059 90.000000 90.000000 90.000000
0.00000 0.00000 0.00000 0.00000 0.00000 0.00000
! Limits for selected parameters (+ steps & BoundCond for SA):
1 0.0000 1.0000 0.0500 1 x_Pb
2 0.0000 1.0000 0.0500 1 y_Pb_SO1
3 0.0000 1.0000 0.0500 1 z_Pb
4 0.0000 1.0000 0.0500 1 x_S
5 0.0000 1.0000 0.0500 1 z_S
6 0.0000 1.0000 0.0500 1 x_O1
7 0.0000 1.0000 0.0500 1 z_O1
8 0.0000 1.0000 0.0500 1 x_O2
9 0.0000 1.0000 0.0500 1 z_O2
10 0.0000 1.0000 0.0500 1 x_O3
11 0.0000 1.0000 0.0500 1 y_O3
12 0.0000 1.0000 0.0500 1 z_O3
! T_ini Anneal Accept NumTemps NumThCyc InitConf
8.000 0.900 0.008 60 0 0
! NCyclM Nsolu Num_Ref Nscalef Algor
150 1 71 1 2
```

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